Notice of References Cited Application/Control No. 10/734,508 Examiner Chad Dickerson Applicant(s)/Patent Under Reexamination ENDO ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2003/0208691	11-2003	Smart et al.	713/201
*	В	US-7,136,941	11-2006	Nguyen et al.	710/15
*	С	US-2002/0030833	03-2002	Kuwata et al.	358/1.9
*	D	US-6,980,699	12-2005	Okada, Satoru	382/284
*	E	US-2003/0084085	05-2003	Breidenbach et al.	709/1
*	F	US-2003/0071903	04-2003	Nakami, Yoshihiro	348/221.1
*	G	US-2002/0116544	08-2002	Barnard et al.	709/324
*	Н	US-2003/0081237	05-2003	Ogiwara et al.	358/1.14
*	1	US-2002/0029277	03-2002	Simpson-Young et al.	709/228
*	J	US-2004/0103124	05-2004	Kupkova, Helena	707/203
*	к	US-7,106,461	09-2006	Kakigi et al.	358/1.12
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	S					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
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	×					

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.